

Notice of References Cited	Application/Control No. 10/717,796		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner David C. Payne		Art Unit 2613	Page 1 of 1

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*	B	US-2003/0123884 A1	07-2003	Willner et al.	398/212
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NON-PATENT DOCUMENTS

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